

Amendments to the Claims:

This listing of the claims will replace all prior versions, and listings, of the claims in the application.

Listing of the Claims:

Claim 1 (currently amended): A circuit having scan circuitry comprising:

- a) a constant power area that receives constant power;
- b) a switched power area that receives interruptible power; wherein the switched power area includes an input for receiving a normal mode clock signal ~~and at least one transistor that is manufactured with a sub-micron semiconductor manufacturing process;~~ and
- e) an inactive state power reduction manager disposed in the constant power area for receiving a sleep signal and responsive thereto for asserting a stop clock signal to stop the normal mode clock, for performing a scan-based state-save by employing the scan circuitry, and for asserting a power control signal that is used to disconnect the switched power area from a power supply pad; and

a selection unit that includes a first input for receiving signals from a source external to the circuit, a second input for receiving signals from the inactive state power reduction manager, a control input for receiving a save-state mode signal, and an output that is coupled to the scan circuitry; wherein the inactive state power reduction manager performs a scan-based state-save by generating the save-state mode signal and by providing signals to the second input of the selection unit.

Claim 2 (currently amended): The circuit of claim 1 further comprising:

d) a power switch coupled to the inactive state power reduction manager for receiving the power control signal and responsive thereto for selectively removing power from the switched power area.

Claim 3 (original): The circuit of claim 2 wherein the power switch is a field effect transistor (FET) having a first electrode coupled to a power source, a second electrode coupled to the switched power area, and a third electrode for receiving the power control signal.

Claim 4 (original): The circuit of claim 1 wherein the inactive state power reduction manager generates a plurality of scan control signals to perform the scan-based state store and scan-based state restore; and wherein the scan control signals includes a scan clock signal.

Claim 5 (original): The circuit of claim 1 wherein the inactive state power reduction manager employs the scan circuitry to save state information and to restore state information.

Claim 6 (original): The circuit of claim 1 wherein the wake-up signal is one of an internal wake-up signal and an external wake-up signal.

Claim 7 (original): The circuit of claim 1 wherein the wake-up signal provided by one of a human trigger, an application, and a timer.

Claim 8 (original): The circuit of claim 1 further comprising:

d) a memory for storing the state information; and

wherein the inactive state power reduction manager provides address signals and memory control signals to the memory and manages memory

operations that read state information from and write state information to the memory.

Claim 9 (previously amended): The circuit of claim 8 wherein the memory is one of a volatile memory, a random access memory, and a non-volatile memory.

Claim 10 (canceled):

Claim 11 (original): The circuit of claim 8 wherein the memory is disposed in one of the constant power area and the switched power area.

Claim 12 (original): The circuit of claim 1 wherein the circuit is implemented in a board level application.

Claim 13 (currently amended): A method for inactive state power reduction for a circuit that has scan circuitry and a switched power portion; wherein the switched power portion includes an input for receiving a normal mode clock signal ~~and at least one transistor that is manufactured with a sub-micron semiconductor manufacturing process~~, the method comprising:

- a) receiving a sleep signal;
responsive to the sleep signal,
- b) stopping the normal mode clock;
- e) performing a state save by employing the scan circuitry and a selection unit that includes a first input for receiving signals from a source external to the circuit, a second input for receiving signals from an inactive state power reduction manager, a control input for receiving a save-state mode signal, and an output that is coupled to the scan circuitry; and

d) disconnecting the switched power portion of the circuit from power.

Claim 14 (original): The method of claim 13 wherein performing a state save using the scan circuitry includes

using the scan circuitry to obtain state information from the circuit; and
storing the state information in a memory.

Claim 15 (canceled):

Claim 16 (previously presented): The method of claim 21 wherein performing a state restore using the scan circuitry includes

reading the previously stored state information from a memory; and
using the scan circuitry to write the state information to the circuit.

Claim 17 (canceled):

Claim 18 (currently amended): A circuit board comprising:

- a) a first integrated circuit having a test access port; an input for receiving a normal mode clock signal ~~and at least one transistor that is manufactured with a sub-micron semiconductor manufacturing process;~~
- b) a second integrated circuit having a test access port ; an input for receiving the normal mode clock signal ~~and at least one transistor that is manufactured with a sub-micron semiconductor manufacturing process;~~
- and
- e) an inactive state power reduction manager coupled to the first integrated circuit and the second integrated circuit for receiving a sleep signal and responsive thereto for asserting a stop clock signal to stop the normal mode clock, for performing a scan-based state save of state

information of the first integrated circuit and the second integrated circuit by using the test access port of the first integrated circuit and the second integrated circuit, respectively, and for asserting a power control signal that is used to disconnect the first integrated circuit and the second integrated circuit from a power supply; and
a selection unit that includes a first input for receiving signals from a source external to the circuit, a second input for receiving signals from the inactive state power reduction manager, a control input for receiving a save-state mode signal from the inactive state power reduction manager, and an output that is coupled to the test access port.

Claim 19 (currently amended): The circuit of claim 18 further comprising:
 ⊕) a power switch coupled to the inactive state power reduction manager for receiving the power control signal and responsive thereto for selectively removing power from the first integrated circuit and the second integrated circuit.

Claim 20 (original): The circuit of claim 18 further comprising:
 a memory for storing the state information; and
 wherein the inactive state power reduction manager provides address signals and memory control signals to the memory and manages memory operations that read state information from and write state information to the memory.

Claim 21 (previously presented): The circuit of claim 1 wherein inactive state power reduction manager receives a wake up signal, and responsive thereto for de-asserting the power control signal that is used to connect the switched power area to the power supply pad, for performing a scan-based state restore by

employing the scan circuitry, and for de-asserting the stop clock signal to resume the normal mode clock.

Claim 22 (currently amended): The method of claim 13 further comprising:

- e) receiving a wake-up signal;
responsive to the wake-up signal,
- f) re-connecting the switched power portion of the circuit to power;
- g) performing a state restore by employing the scan circuitry; and
- h) re-starting the normal mode clock.

Claim 23 (previously presented): The circuit board of claim 18 wherein inactive state power reduction manager receives a wake up signal, and responsive thereto for de-asserting the power control signal that is used to re-connect the first integrated circuit and the second integrated circuit to the power supply, for performing a scan-based state restore for restoring state information to the first integrated circuit and the second integrated circuit by using the test access port of the first integrated circuit and the second integrated circuit, respectively, and for de-asserting the stop clock signal to resume the normal mode clock.